

The absolute measurement of the Photo Detection Efficiency (PDE) of a SiPM over the whole visible range using continuous light is not a straightforward task as it requires the accurate determination of the detector gain. We have developed at LAL a process to achieve an absolute PDE with an accuracy of $\pm 5\%$.

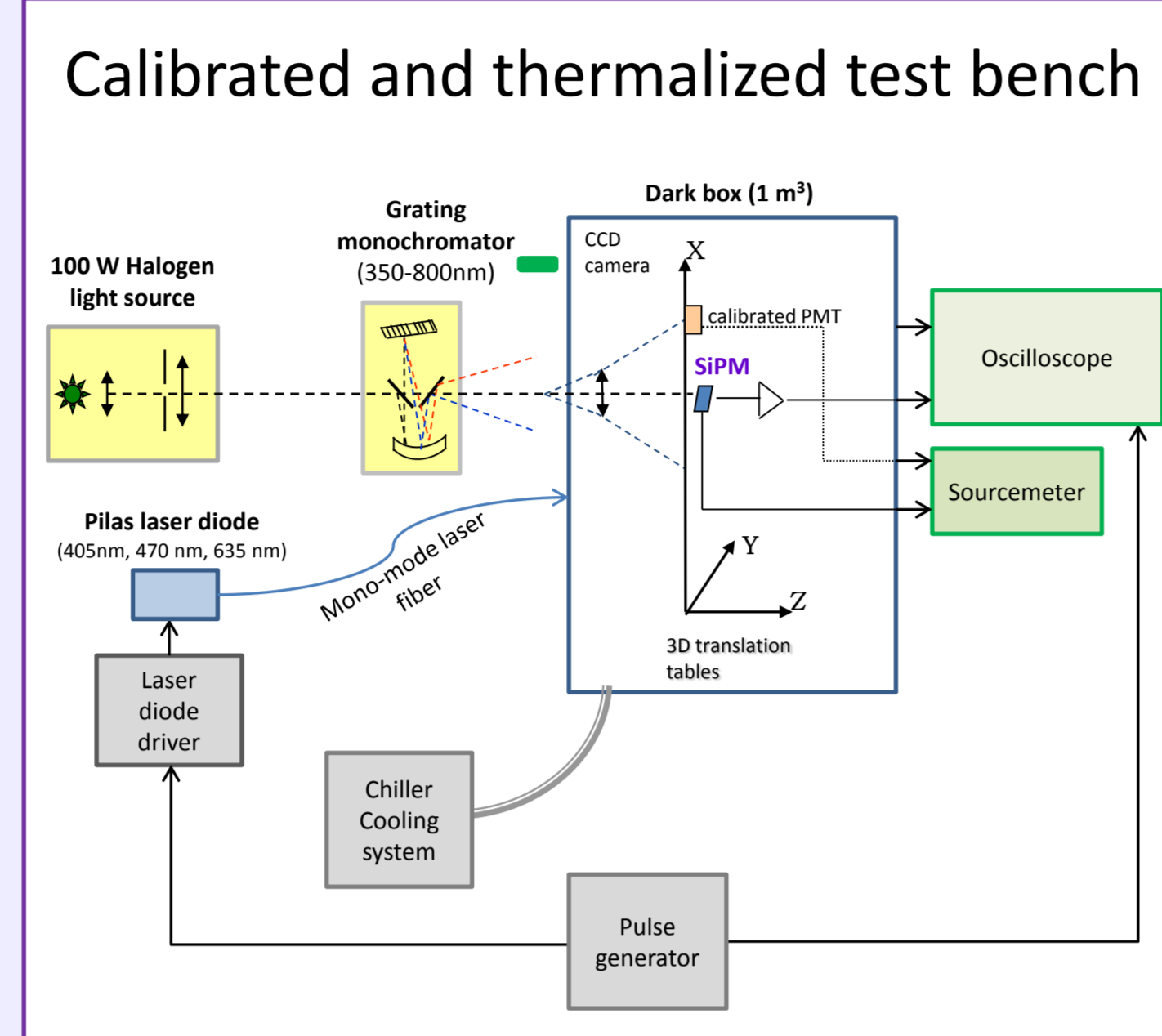
Test Bench Description

Test bench equipments:

- Lecroy 740Zi oscilloscope
- 2612 Keithley sourcemeter
- Pilas Laser diode (407, 467, 635 nm)
- Oriol grating monochromator
- Chiller cooling system
- Hamamatsu R7400U-02 calibrated PMT

Test bench performances:

- $20^\circ\text{C} \pm 0.1^\circ\text{C}$
- 40000 events statistic
- 50 ps laser pulse width
- 1 nm wavelength control
- 1 nA current measurement sensitivity
- $\pm 5\%$ light flux calibration



PDE measurement methods

$$PDE(\%) = 100 \times \frac{Nb \text{ Photon}_{converted}}{Flux_{incident}}$$

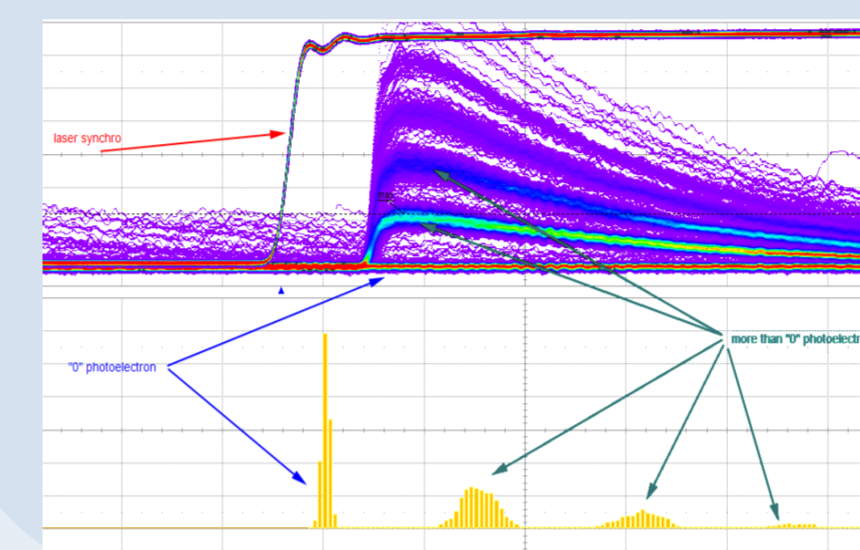
$$Flux_{incident} (ph / mm^2 / s) = \frac{I_{PMT} \times \lambda \times q_e}{h \times c \times R_{S_{PMT}} \times G_{PMT} \times S_{PMT}}$$

I_{PMT} PMT photo generated current (A), $R_{S_{PMT}}$ PMT anode sensibility (A/W), G_{PMT} PMT gain, S_{PMT} PMT illuminated surface (mm^2)

Counting method

- triggered laser \rightarrow few photons Dirac pulses
- Poisson probability distribution law
- 40000 events statistic $\rightarrow \pm 5\%$ accuracy

$$Nb \text{ Photon}_{converted} = -\ln(P(0))$$



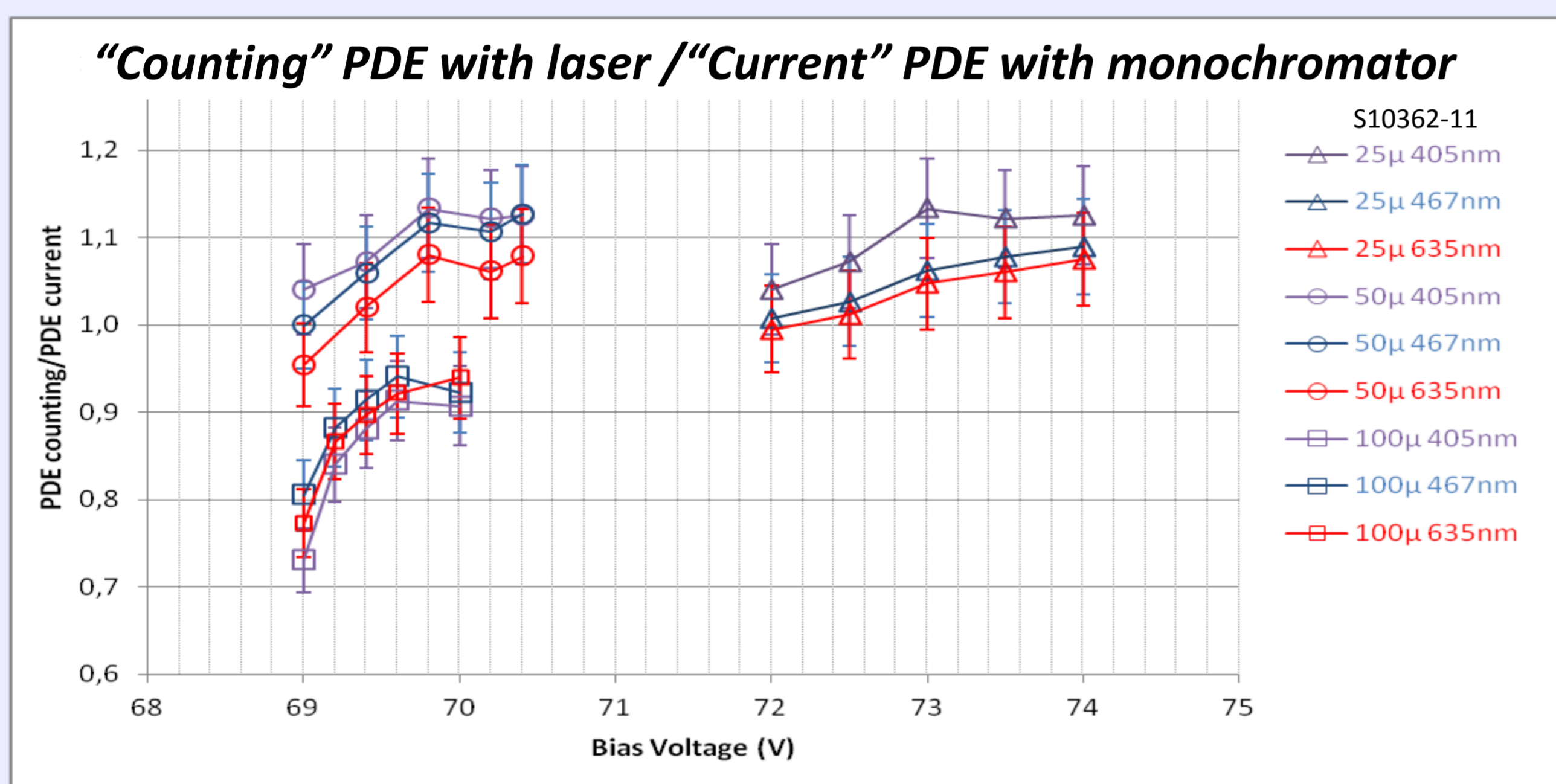
Current method

- continuous monochromatic source
- incident flux $< 10^7$ ph/ mm^2/s \ll SiPM saturation

$$Nb \text{ Photon}_{converted} = \frac{(I_{light} - I_{dark})}{q_e \times G_{SiPM}}$$

G_{SiPM} : SiPM gain measured in dark conditions
 I_{light} : SiPM photo generated current (A)
 I_{dark} : SiPM dark current (A)

Absolute PDE of MPPC S10362-11 @ 20°C Comparison of the 2 methods

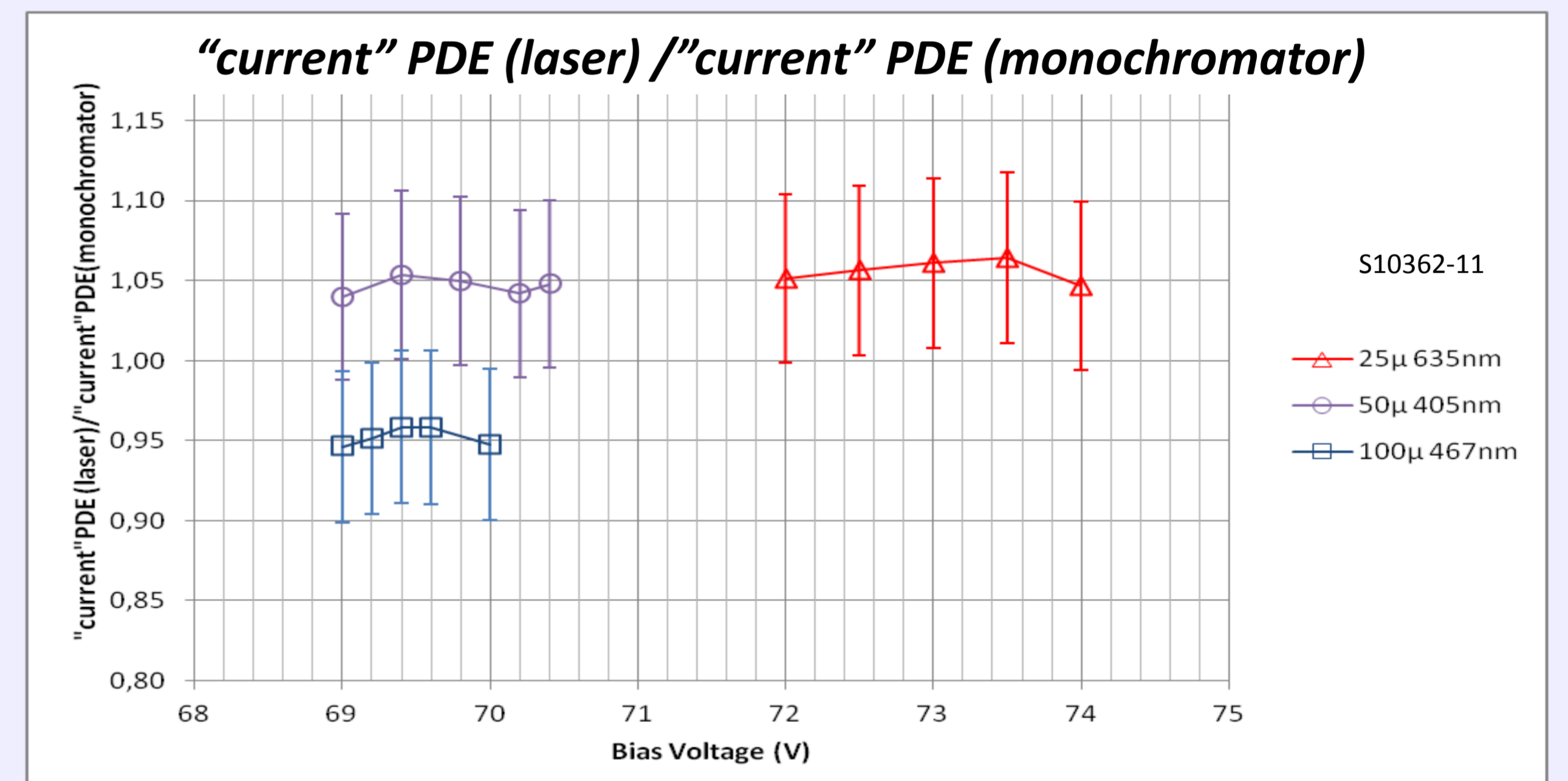


- PDE ratio:**
- $0.8 < \text{ratio} < 1.1$
 - ratio \nearrow with V_{bias}
 - wavelength uncorrelated

- Hypothesis:**
- error in incident flux estimation? \rightarrow no, calibration of the bench $\pm 5\%$
 - error in the SiPM gain measurement? \rightarrow maybe ...
 - variation of the temperature? \rightarrow no, variation = $\pm 0,1^\circ\text{C}$

PDE measurement with laser & monochromator using the "Current method"

2 different light sources, the ratio of the PDE is independant from the SiPM gain

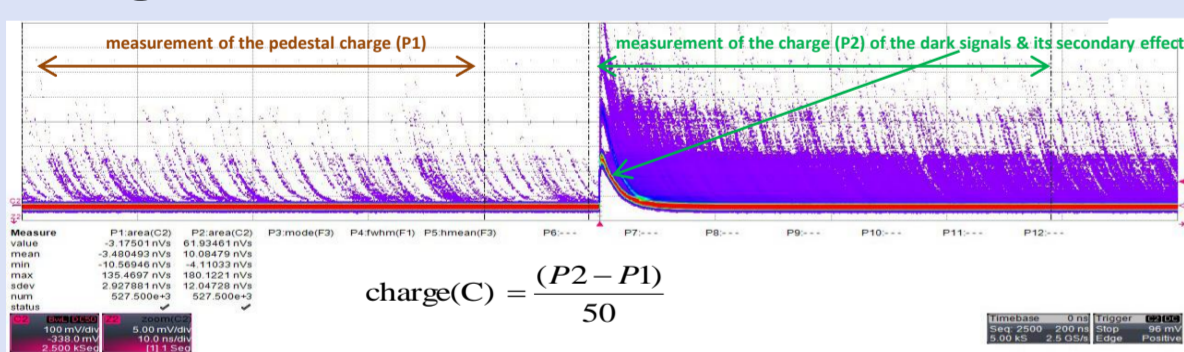


- PDE ratio:**
- ratio = $1 \pm 5\%$
 - no variation with V_{bias}

- Conclusion:**
- error on the SiPM gain measurement = 10 – 20 %

SiPM Gain measurements

Measured dark Gain: mean SiPM charge integration in a window of 800 ns



Calculated Gain: determined from the "Counting method" PDE (PDE_{count}) measurement and photo generated current ($I_{light} - I_{dark}$):

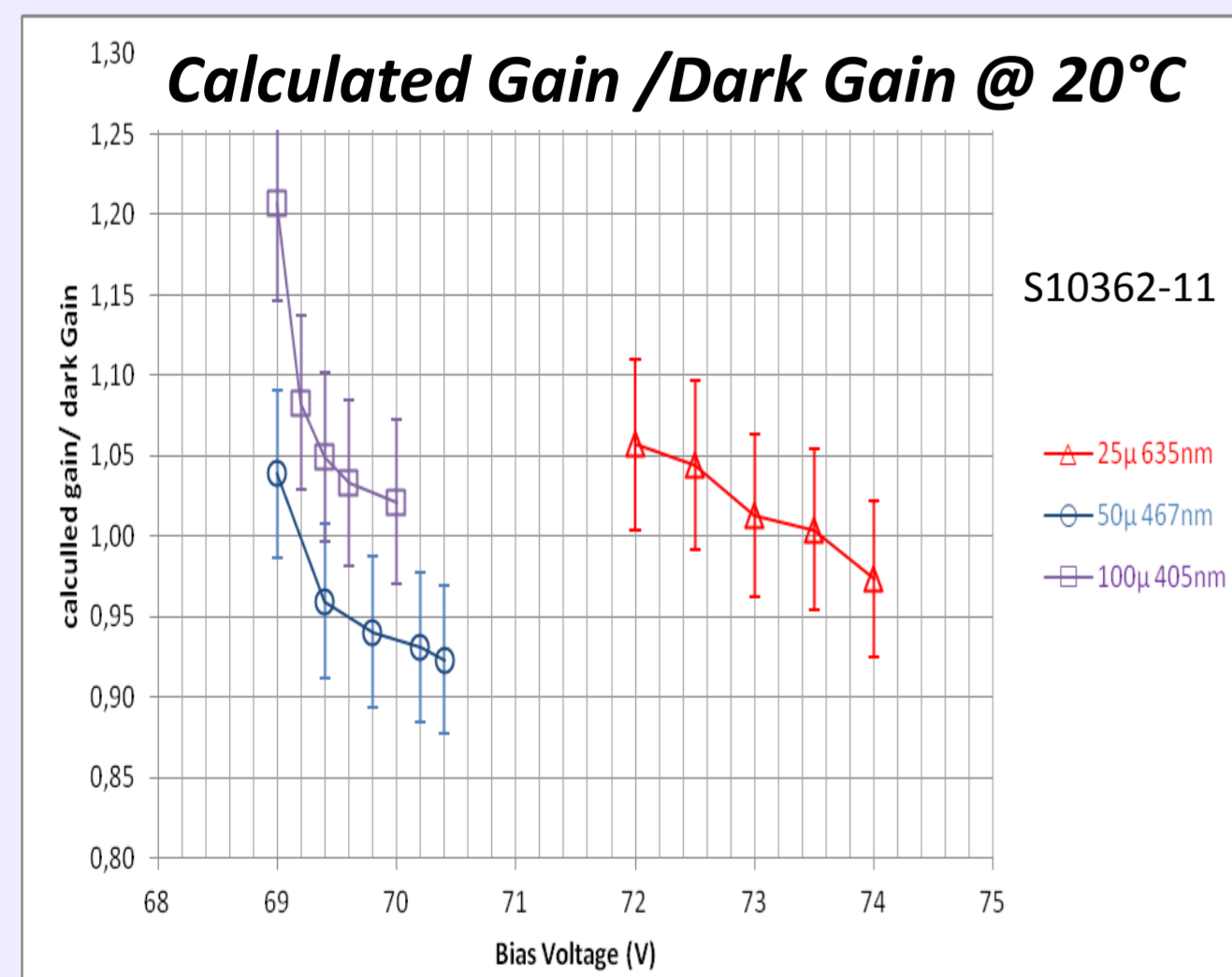
$$Gain_{calculated} = \frac{(I_{light} - I_{dark})}{Flux_{incident} \times PDE_{count} \times q_e}$$

I_{light} SiPM photo generated current (A), I_{dark} SiPM dark current (A), $Flux_{incident}$ of the laser (ph/ mm^2/s).

- Gain ratio:**
- $0.9 < \text{ratio} < 1.2$ as expected
 - ratio \searrow with V_{bias}

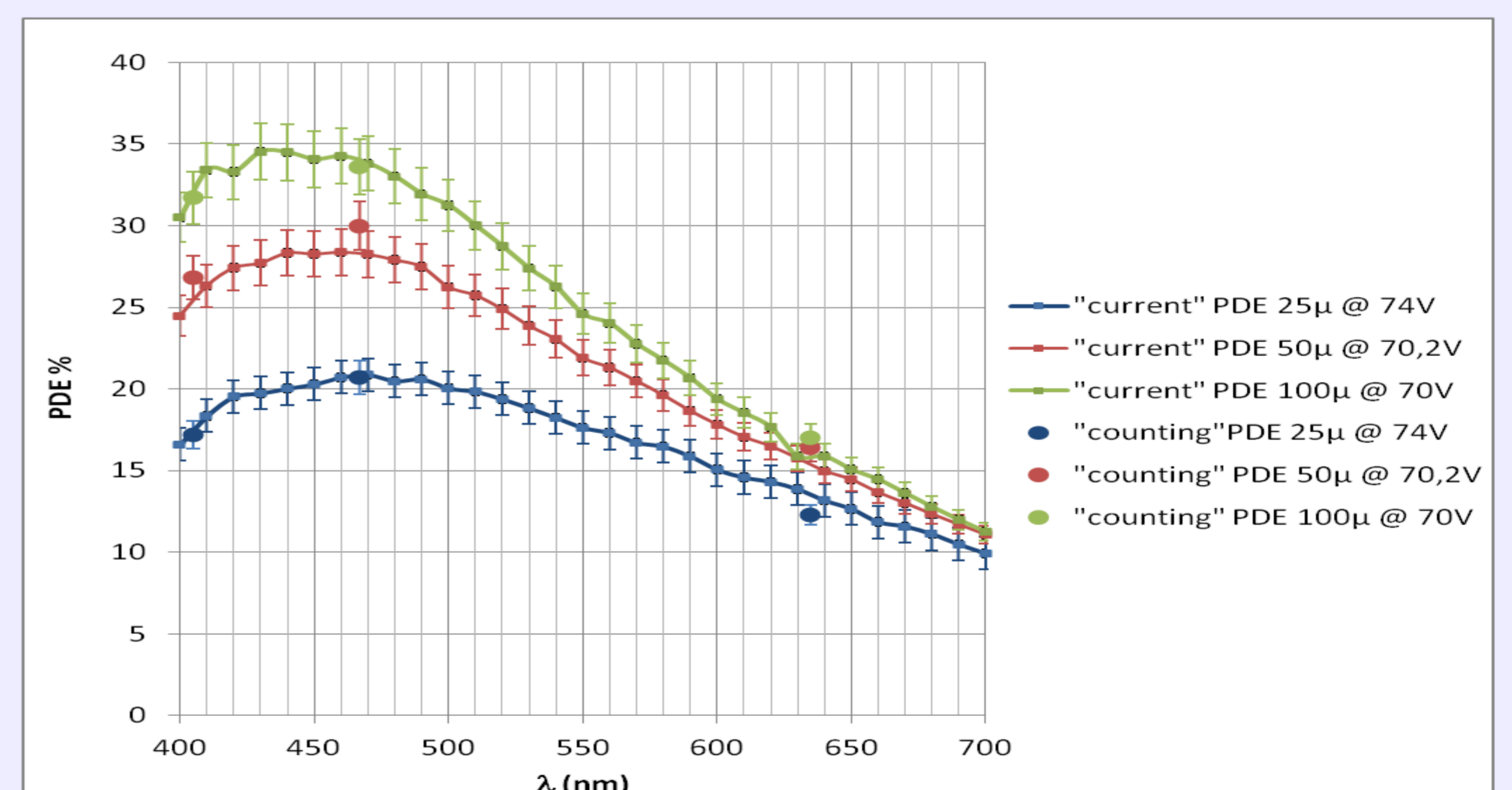
Conclusion:

the SiPM gain measured in dark condition is not precise enough to give an absolute PDE at 5% \rightarrow need of an indirect method to evaluate it (via the counting PDE)



S10362-11 absolute PDE $400 \text{ nm} < \lambda < 700 \text{ nm}$ @ 20°C

SiPM gain determined owing to the counting PDE measurement @ 405 nm



$\pm 5\%$ agreement between the measurements in pulsed and continuous light
= limit of the bench calibration accuracy

Conclusion

- **5% absolute PDE accuracy @ all V_{bias} and λ (400 – 700 nm)**
- the SiPM gain is determined from the "current" PDE & "counting" PDE comparison \rightarrow **need of a very well calibrated test bench**
- **the direct gain measurement in dark conditions gives errors of 10 to 20 % \rightarrow need of detailed analysis of secondary effects (after-pulses, crosstalk) and dark noise distribution (ongoing study in collaboration with Fermilab).**